Investigation of Revised Sampling Method for on-site National Safeguards Inspection

Haneol Lee*, Yewon Kim, Hyun Ju Kim, Jung Yoon Choi, Ju Young Jeon Korea Institute of Nuclear non-proliferation and Control(KINAC)

* haneol@kinac.re.kr



Introduction

- Notification (NSSC No. 2017-83) requires "on-site verification" for national safeguards inspection
- The KINAC has been developing an independent inspection supporting program, which includes sampling planning
- This research identified the limitations of IAEA sampling planning and investigated the revised sampling method for national inspection

Research Overview

 Investigation of the optimized sampling method which satisfies both verification criteria and minimized inspection burden

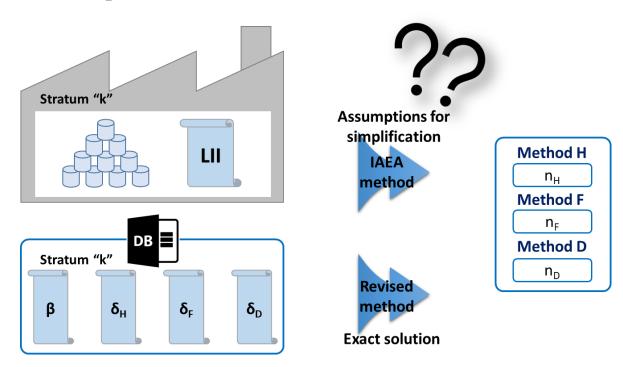


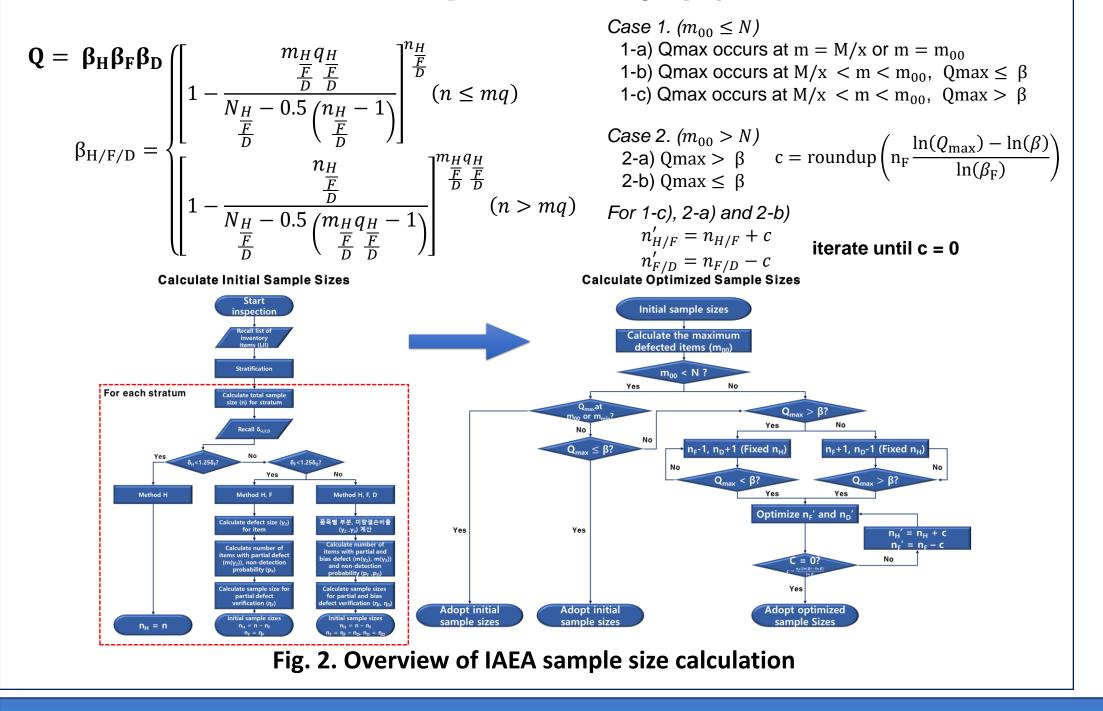
Fig. 1. Overview of the research

IAEA's Sampling Method

 Calculate initial sample sizes for each stratum & verification method using polynomial adjusted hypergeometric distribution

$$\begin{split} & n_{\rm H} = roundup \left(N \big(1 - \beta^{(1/D)} \big) \right) \quad \beta = \frac{N - D C_{n_{\rm H}} \times_D C_0}{N C_{n_{\rm H}}} \approx (1 - \frac{n_{\rm H}}{N})^D \\ & n_{\rm F,D} = \ln \left(\beta \right) / \ln \big(1 - M / \gamma_{\rm F,D}' N x \big) \quad \beta = \sum_{k=0}^{n_{\rm HD}} \frac{m (\gamma_{\rm F,D}) C_{k_{\rm F,D}} \times_{(N-m (\gamma_{\rm F,D}))} C_{(n_{\rm F,D} - k_{\rm F,D})}}{N C_{n_{\rm HD}}} (1 - p_{\rm F,D})^{k_{\rm F,D}} \approx (1 - \frac{m (\gamma_{\rm F,D}) p_{\rm F,D}}{N})^{n_{\rm F,D}} \end{split}$$

• Optimize sample size by iteration to converge Qmax to be non-detection probability (β) of a stratum



Revised Sampling Method

- Calculate total sample size for each stratum by calculating the exact solution of hypergeometric distribution
- Calculate the initial sample sizes for partial and bias defect verification by calculating the exact solution of hypergeometric distribution using iteration $\beta = 0.8$ β_E η_E

$$\beta = \frac{\binom{N-D}{N}C_n \times {}_DC_0}{NC_n}$$

$$\beta_{F,D} = \sum_{k=0}^n \frac{\binom{N-m(\gamma)}{N}C_{(n-k)} \times {}_{m(\gamma)}C_k}{NC_n} (1-p)^k$$

For $D \le m(\gamma) \le m_{00}$, Calculate n at $\max(\beta_{F,D})$, which satisfies $\beta_{F,D} < \beta$

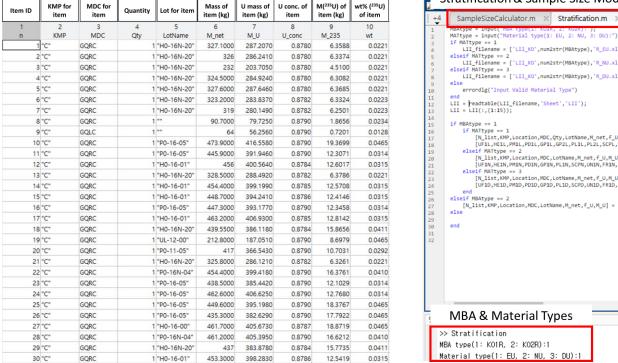
eta=0.8 eta_F n_F $n_$

Fig. 3. Iteration for revised initial sampling

 Optimize the initial sample sizes using the IAEA's method without polynomial adjustment

Results

- Develop a stratification program for a FFP
- Calculate sample sizes for each stratum and verification methods using the IAEA and revised sampling methods



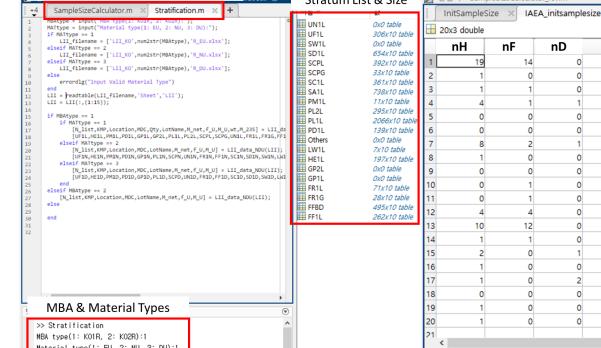


Fig. 4. List of inventory items (left) and stratification & sample size calculator (right)

 Reduced total sample sizes or sample sizes with sensitive verification methods using revised

sampling method

 Reduced inspection burden for inspectors and facilities while maintaining the nondetection probability

Stratum	IAEA's method			Revised method		
	n _H	n _F	$n_{\scriptscriptstyle D}$	n _H	n _F	$n_{\scriptscriptstyle D}$
UF1L	19	14	0	21	12	0
HE1L	1	0	0	1	0	0
PM1L	1	1	0	1	1	0
PD1L	4	1	1	3	1	1
GP1L	0	0	0	0	0	0
GP2L	0	0	0	0	0	0
PL1L	8	2	1	9	1	1
PL2L	1	0	0	0	0	1
UN1L	0	0	0	0	0	0
FR1L	0	1	0	0	1	0
FR1G	0	1	0	0	1	0
FF1L	4	4	0	4	4	0
FFBD	10	12	0	10	12	0
SC1L	1	1	0	1	0	1
SCPL	2	0	1	2	0	1
SCPG	1	0	0	1	0	0
SD1L	1	0	2	2	0	1
SW1L	0	0	0	0	0	0
LW1L	1	0	0	1	0	0
SA1L	1	0	0	1	0	0

Fig. 5. Sample sizes (IAEA: blue, Rev: orange)

Conclusion

- The IAEA method overestimates sample size due to the polynomial adjustment of hypergeometric distribution
- The research investigated to calculate the exact solution for sampling, which reduces inspection burden
- Future work will include the optimization of the IAEA's sample optimization process

References

- [1] Subparagraph 2 of Article 4 of Regulations on the Safeguards Inspection of SNMs of the ROK, NSSC notification No. 2017-83, 2017.
- [2] IAEA, Reference Manual: Statistical Concepts and Techniques for IAEA Safeguards, IAEA-SG-SCT-5, 1998.
- [3] J. L. Jaech, Algorithms to calculate sample sizes for inspection sampling plans, IAEA-STR-261(Rev.0), 1990.